

3.3V CMOS 18-BIT READ/WRITE BUFFER WITH BUS-HOLD

FEATURES:

- 0.5 MICRON CMOS Technology
- Typical tsκ(0) (Output Skew) < 250ps
- ESD > 2000V per MIL-STD-883, Method 3015;
 > 200V using machine model (C = 200pF, R = 0)
- 0.635mm pitch SSOP, 0.50mm pitch TSSOP, and 0.40mm pitch TVSOP packages
- Extended commercial range of 40°C to + 85°C
- $Vcc = 3.3V \pm 0.3V$, Normal Range
- Vcc = 2.7V to 3.6V, Extended Range
- Vcc = 2.5V ± 0.2V
- CMOS power levels (0.4µW typ. static)
- Rail-to-Rail output swing for increased noise margin

Drive Features for ALVCH16701:

- High Output Drivers: ±24mA
- Suitable for heavy loads

APPLICATIONS:

- 3.3V High Speed Systems
- 3.3V and lower voltage computing systems

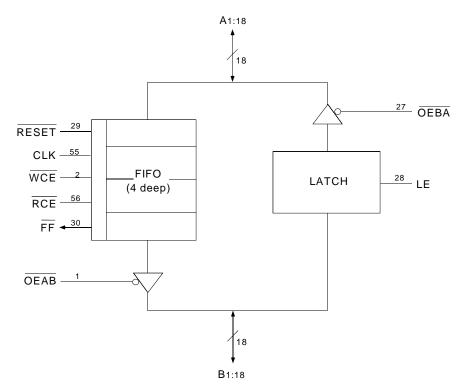
DESCRIPTION:

This 18-bit read/write buffer is built using advanced dual metal CMOS technology. The ALVCH16701 is equipped with a four deep FIFO and a read-back latch. It can be used as a read/write buffer between a CPU and a memory or to interface a high-speed bus and a slow peripheral. The A-to-B (write) path has a four deep FIFO for pipelined operations. The FIFO can be reset and a FIFO full condition is indicated by the full flag (FF). The B-to-A (read) path has a latch.

The ALVCH16701 has been designed with a ± 24 mA output driver. This driver is capable of driving a moderate to heavy load while maintaining speed performance.

The ALVCH16701 has "bus-hold" which retains the inputs' last state whenever the input goes to a high impedance. This prevents floating inputs and eliminates the need for pull-up/down resistor.

FUNCTIONAL BLOCK DIAGRAM

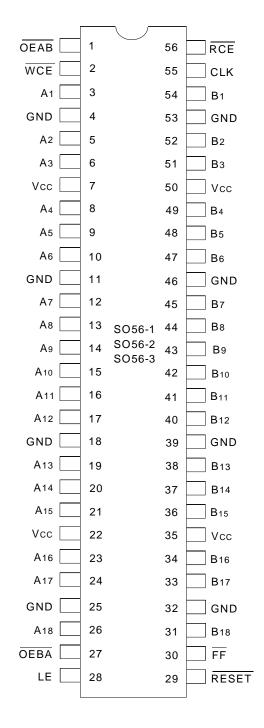


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EXTENDED COMMERCIAL TEMPERATURE RANGE

SEPTEMBER 1999

PIN CONFIGURATION



SSOP/ TSSOP/TVSOP TOP VIEW

ABSOLUTE MAXIMUM RATING (1)

Symbol	Description	Max.	Unit
VTERM ⁽²⁾	Terminal Voltage	– 0.5 to + 4.6	V
	with Respect to GND		
VTERM(3)	Terminal Voltage	– 0.5 to	V
	with Respect to GND	Vcc + 0.5	
Tstg	Storage Temperature	– 65 to + 150	°C
Ιουτ	DC Output Current	– 50 to + 50	mA
Ік	Continuous Clamp Current,	± 50	mA
	$V_{I} < 0 \text{ or } V_{I} > V_{CC}$		
Іок	Continuous Clamp Current, Vo < 0	- 50	mA
Icc	Continuous Current through	±100	mA
lss	each Vcc or GND		
NOTES	•	•	NEW16link

NOTES:

 Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

2. Vcc terminals.

3. All terminals except Vcc.

CAPACITANCE (TA = +25°C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Тур.	Max.	Unit
Cin	Input Capacitance	VIN = 0V	5	7	pF
Соит	Output Capacitance	Vout = 0V	7	9	pF
Ci/o	I/O Port Capacitance	Vin = 0V	7	9	pF

NOTE:

1. As applicable to the device type.

PIN DESCRIPTION

Pin Names	I/O	Description
A1-18	I/O	18 bit I/O port ⁽¹⁾
B1-18	I/O	18 bit I/O port ⁽¹⁾
CLK	I	Clock for write path FIFO. Clocks data into FIFO when \overline{WCE} is low, clocks data out of FIFO when \overline{RCE} is low. When FIFO is full all further writes to the FIFO are inhibited. When FIFO is empty all reads from the FIFO are inhibited. CLK also resets the FIFO when \overline{RESET} is low.
WCE	I	Enable pin for FIFO input clock.
RCE	I	Enable pin for FIFO output clock.
FF	0	Write path FIFO full flag. Goes low when FIFO is full.
RESET	I	Synchronous FIFO reset - when low CLK resets the FIFO. The FIFO pointers are initialized to the "empty" condition and FIFO output is forced high (all ones). The FIFO full flag (FF) will be high immediately after reset.
OEAB	I	Output enable pin for B port
OEBA	I	Output enable pin for A port
LE	I	Read path latch enable pin. When high, data flows transparently from B port to A port, B data is latched on the falling edge of LE.

NOTE:

1. These pins have "Bus-Hold." All other pins are standard inputs, outputs, or I/Os.

FUNCTION DESCRIPTION

This device is useful as a read/write buffer for modular high end designs. It provides multi-level buffering in the write path and single deep buffering in the read path, and is suited to write back cache implementation. The read path provides a transparent latch.

The four deep FIFO uses one clock with two clock enable pins, WCE and RCE to clock data in and out. The FIFO has an external full flag which goes LOW when the FIFO is full. Internal read and write pointers keep track of the words stored in the FIFO. A write attempt to a full FIFO is ignored. An attempt read from an empty FIFO will have no effect and the last read data remains at the output of the FIFO. The FIFO may be reset by the synchronous $\overrightarrow{\text{RESET}}$ input. This resets the read and write pointers to the original "empty" condition and also sets all B outputs = 1. Simultaneous read and write attempts (clock data into FIFO as well as clock data out of FIFO) are possible except on FIFO empty and full boundaries. When the FIFO is empty, and a simultaneous read and write is attempted, the read is ignored while the write is executed. If the same is attempted when the FIFO is full, the write is ignored while the read is executed. Normal operation of the four deep FIFO in the write path is independent of the read path operation.

FUNCTION TABLE⁽¹⁾

INPUTS					OUT	IPUTS	NOTES
OEBA	OEAB	LE	RESET	CLK	Ах	Вх	
Н	Н	Н	Н	\uparrow	Q(B) Bus Hold	Q ₀ (A) -4CLKS Bus Hold	
L	Н	Н	Н	\uparrow	B to A		Transparent Mode
L	Н	L	Н	\uparrow	О ₀ (В)		
Н	Н	Х	Н	\uparrow	Q ₀ (A) Bus Hold	Q ₀ (B) Bus Hold	
Н	L	Х	Н	↑		A to B - 4 CLKS	
L	L	L	Н	Ŷ	Q ₀ (B) Bus Hold	Q ₀ (B) - 4 CLKS Bus Hold	Case not recommended

NOTE:

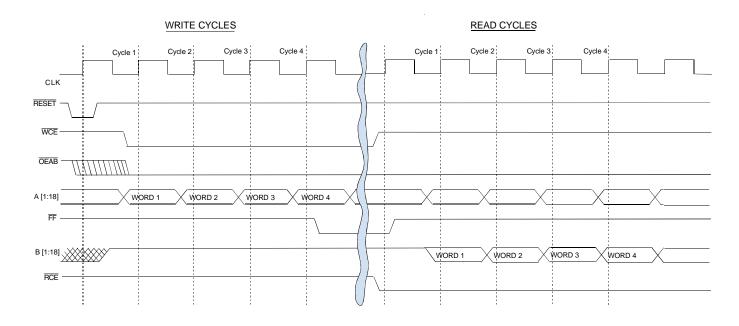
1. H = HIGH Voltage Level

L = LOW Voltage Level

X = Don't Care

 \uparrow = LOW-to-HIGH Transition

TIMING DIAGRAM



DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Condition: TA = - 40°C to +85°C

Symbol	Parameter	Test C	Conditions	Min.	Typ. ⁽¹⁾	Max.	Unit
Vih	Input HIGH Voltage Level	Vcc = 2.3V to 2.7V		1.7	_	_	V
		Vcc = 2.7V to 3.6V		2	—	_	
VIL	Input LOW Voltage Level	Vcc = 2.3V to 2.7V		_	_	0.7	V
		Vcc = 2.7V to 3.6V		_	_	0.8	
Іін	Input HIGH Current	Vcc = 3.6V	VI = VCC	_	_	± 5	μA
lil	Input LOW Current	Vcc = 3.6V	VI = GND	_	_	± 5	
Іотн	High Impedance Output Current	Vcc = 3.6V	Vo = Vcc	_	_	± 10	μA
lozl	(3-State Output pins)		Vo = GND	_	_	± 10	μA
Vik	Clamp Diode Voltage	VCC = 2.3V, IIN = - 18mA	·	_	- 0.7	- 1.2	V
Vн	Input Hysteresis	Vcc = 3.3V		_	100	_	mV
ICCL	Quiescent Power Supply Current	Vcc = 3.6V		_	0.1	40	μA
Іссн		VIN = GND or VCC					
lccz							
ΔICC	Quiescent Power Supply	One input at Vcc - 0.6V,	One input at Vcc – 0.6V,		—	750	μA
	Current Variation	other inputs at Vcc or GND					NFW16link

NOTE:

1. Typical values are at Vcc = 3.3V, +25°C ambient.

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BUS-HOLD CHARACTERISTICS

Symbol	Parameter ⁽¹⁾		Test Conditions		Typ. ⁽²⁾	Max.	Unit
Івнн	Bus-Hold Input Sustain Current	Vcc = 3.0V	VI = 2.0V	- 75	-		μA
IBHL			VI = 0.8V	75	—	_	
Івнн	Bus-Hold Input Sustain Current	Vcc = 2.3V	VI = 1.7V	- 45	—	_	μA
IBHL			VI = 0.7V	45	—	_	
Івнно	Bus-Hold Input Overdrive Current	Vcc = 3.6V	VI = 0 to 3.6V	—	—	± 500	μA
Ibhlo							NEW16lin

NOTES:

1. Pins with Bus-hold are identified in the pin description.

2. Typical values are at Vcc = 3.3V, +25°C ambient.

OPERATING CHARACTERISTICS, T_A = 25^{\circ}C

				$Vcc = 2.5V \pm 0.2V$	$Vcc = 3.3V \pm 0.3V$	
Symbol	Parameter	Test Conditions		Typical	Typical	Unit
Cpd	Power Dissipation Capacitance Outputs enabled		CLK Toggling	28	31	pF
		CL = 0pF, f = 10Mhz	One Bit Toggling	26	29	
Cpd	Power Dissipation Capacitance Outputs enabled		CLK Toggling	10	11	pF
			One Bit Toggling	9	10	

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test C	Test Conditions ⁽¹⁾		Max.	Unit
Vон	Output HIGH Voltage	Vcc = 2.3V to 3.6V	Iон = – 0.1mA	Vcc - 0.2	-	V
		Vcc = 2.3V	Iон = – 6mA	2	-	
		Vcc = 2.3V	Iон = – 12mA	1.7	_	
		Vcc = 2.7V		2.2	_	
		Vcc = 3.0V		2.4	_	
		Vcc = 3.0V	Iон = – 24mA	2	_	
Vol	Output LOW Voltage	Vcc = 2.3V to 3.6V	IOL = 0.1mA	_	0.2	V
		Vcc = 2.3V	IOL = 6mA	_	0.4	
			IOL = 12mA	_	0.7	
		Vcc = 2.7V	IOL = 12mA	_	0.4]
		Vcc = 3.0V	IOL = 24mA	_	0.55	1
	•	•	•	•	•	NEW16lin

NOTE:

1. VIH and VIL must be within the min. or max. range shown in the DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE table for the appropriate Vcc range. TA = − 40°C to + 85°C.

SWITCHING CHARACTERISTICS (1)

			Vcc =	= 2.7V	$Vcc = 3.3V \pm 0.3V$			
	Parameter	Test Conditions	Min.	Max.	Min.	Max.	Unit	
PROPA	GATION DELAYS					•		
1	B1-18 to A 1-18	Read path/latch	_	_	1.5	4.5	ns	
2	LE (LOW to HIGH) to A 1-18	Read path/latch	_	—	1.5	4.5	ns	
3	CLK to F F	Write path	_	_	1.5	5.5	ns	
4	CLK to B 1-18	Write path	_	_	1.5	5.5	ns	
5	Output Skew ⁽²⁾	Write path	_	_	_	1	ns	
SETUP	& HOLD TIMES				·		.	
6	A1-18 to CLK (LOW to HIGH) Setup	Write path	_	_	1.8	_	ns	
7	A1-18 to CLK (LOW to HIGH) Hold	Write path	_	_	1	_	ns	
8	B1-18 to LE (HIGH to LOW) Setup	Read path/latch	_	—	1.8	_	ns	
9	B1-18 to LE (HIGH to LOW) Hold	Read path/latch	_	_	1	_	ns	
10	WCE, RCE (LOW) to CLK Setup	Write path	_	_	3.5	_	ns	
11	WCE, RCE (LOW) to CLK Hold	Write path	—	—	0.5	_	ns	
12	RESET (LOW) to CLK Setup	Write path	_	_	1.8	_	ns	
13	RESET (LOW) to CLK Hold	Write path	_	_	1	_	ns	
ENABL	E & DISABLE TIMES				·		.	
14	OEBA LOW to A 1-18 Enable	Write path	_	_	1.5	6	ns	
15	OEBA HIGH to A 1-18 Disable	Write path	_	_	1.5	5.7	ns	
16	OEAB LOW to B 1-18 Enable	Read path	—	—	1.5	6	ns	
17	OEAB HIGH to B 1-18 Disable	Read path	_	_	1.5	5.7	ns	
MINIMU	M PULSE WIDTHS				·		.	
18	CLK HIGH or LOW Pulse Width	Write path	_	_	5	_	ns	
19	LE HIGH Pulse Width	Read path/latch	_	—	5	_	ns	
	-			-			•	
19	Clock Frequency		_	—		83	MHz	
20	Clock Cycle Time		_	_	12	_	ns	

NOTES:

1. See test circuits and waveforms. TA = -40° C to $+85^{\circ}$ C.

2. Skew between any two outputs of the same package and switching in the same direction.

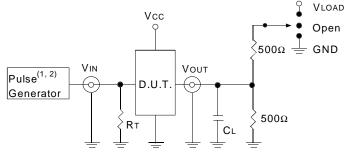
IDT74ALVCH16701 3.3V CMOS 18-BIT READ/WRITE BUFFER WITH BUS-HOLD

TEST CIRCUITS AND WAVEFORMS

TEST CONDITIONS

Vcc ⁽¹⁾ = 3.3V±0.3V	Vcc ⁽¹⁾ = 2.7V	Vcc ⁽²⁾ = 2.5V±0.2V	Unit
6	6	2 x Vcc	V
2.7	2.7	Vcc	۷
1.5	1.5	Vcc / 2	V
300	300	150	mV
300	300	150	mV
50	50	30	pF NEW16link
	6 2.7 1.5 300 300	6 6 2.7 2.7 1.5 1.5 300 300 300 300	6 6 2 x Vcc 2.7 2.7 Vcc 1.5 1.5 Vcc / 2 300 300 150 300 300 150 50 50 30

TEST CIRCUITS FOR ALL OUTPUTS



DEFINITIONS:

- CL= Load capacitance: includes jig and probe capacitance.
- RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

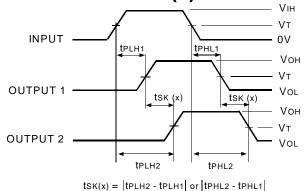
NOTES:

- 1. Pulse Generator for All Pulses: Rate \leq 10MHz; tF \leq 2.5ns; tR \leq 2.5ns.
- 2. Pulse Generator for All Pulses: Rate \leq 10MHz; tF \leq 2ns; tR \leq 2ns.

SWITCH POSITION

Test	Switch
Open Drain	VLOAD
Disable Low	
Enable Low	
Disable High	GND
Enable High	
All Other tests	Open
	NEW16link

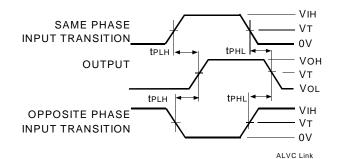
OUTPUT SKEW - TSK (x)



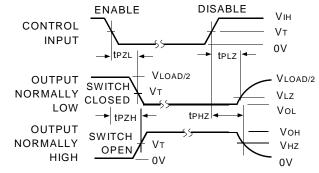
NOTES:

- 1. For tsk(o) OUTPUT1 and OUTPUT2 are any two outputs.
- 2. For tsk(b) OUTPUT1 and OUTPUT2 are in the same bank.

PROPAGATION DELAY



ENABLE AND DISABLE TIMES

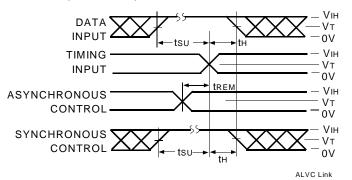


NOTE:

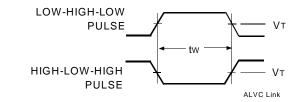
ALVC Link

ALVC Link 1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.

SET-UP, HOLD, AND RELEASE TIMES

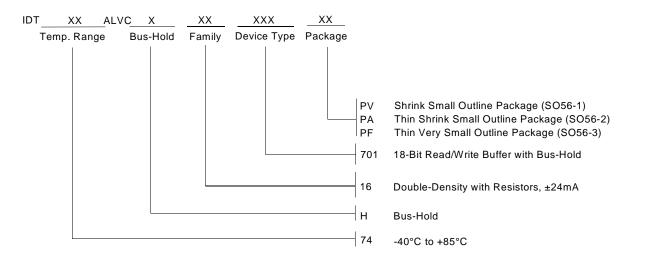


PULSE WIDTH



ALVC Link

ORDERING INFORMATION





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